

60V N+N-Channel Enhancement Mode MOSFET

Description

The AP2N7002DW uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 10V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

$V_{DS} = 60V$ $I_D = 0.3A$

$R_{DS(ON)} < 2100m\Omega$ @ $V_{GS}=10V$ (Type: 1600m Ω)

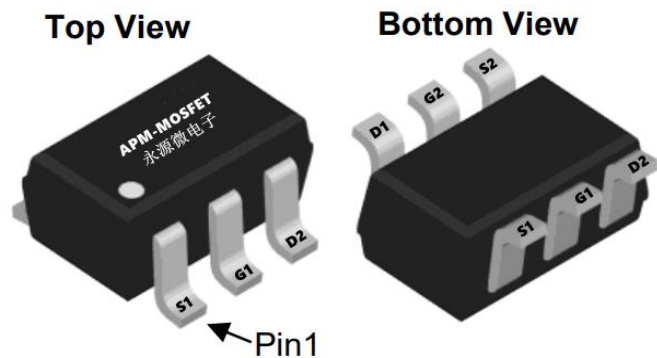
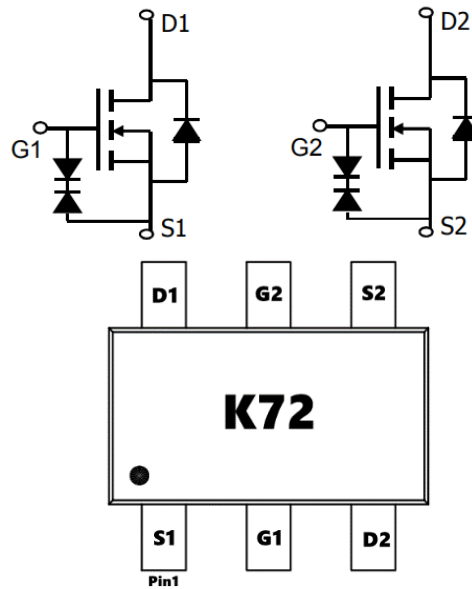
ESD=2KV HBM

Application

Battery protection

Load switch

Uninterruptible power supply



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP2N7002DW	SOT363-6L	K72	3000

Absolute Maximum Ratings@ $T_J=25^\circ C$ (unless otherwise specified)

Symbol	Parameter	Max.	Units
V_{DS}	Drain-Source Voltage	60	V
V_{GS}	Gate-Source Voltage	± 20	V
$I_D @ T_C=25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V^1$	0.3	A
$I_D @ T_C=100^\circ C$	Continuous Drain Current, $V_{GS} @ 10V^1$	0.15	A
IDM	Pulsed Drain Current	1	A
$P_D @ T_C=25^\circ C$	Power Dissipation	0.38	W
T_J, T_{STG}	Operating and Storage Temperature Range	-55 to +150	$^\circ C$
$R_{\theta JA}$	Thermal Resistance Junction-Ambient ¹	135	$^\circ C/W$
$R_{\theta JC}$	Thermal Resistance Junction-Case ¹	100	$^\circ C/W$

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Electrical Characteristics ($T_J=25^{\circ}\text{C}$, unless otherwise noted)

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Units
V(BR)DSS	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=10\mu A$	60	67	-	V
IDSS	Zero Gate Voltage Drain Current	$V_{DS}=60V, V_{GS}=0V,$	-	-	1	μA
IGSS	Gate to Body Leakage Current	$V_{DS}=0V, V_{GS}=\pm 20V$	-	-	± 10	μA
VGS(th)	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu A$	1.0	1.3	2.5	V
RDS(on)	Static Drain-Source on-Resistance	$V_{GS}=10V, I_D=0.3A$	-	1600	2100	m Ω
RDS(on)	Static Drain-Source on-Resistance	$V_{GS}=4.5V, I_D=0.2A$	-	1900	2700	m Ω
Ciss	Input Capacitance	$V_{DS}=25V, V_{GS}=0V, f=1.0MHz$	-	28	-	pF
Coss	Output Capacitance		-	11	-	pF
Crss	Reverse Transfer Capacitance		-	4	-	pF
Qg	Total Gate Charge	$V_{DS}=10V, I_D=0.3A, V_{GS}=4.5V$	-	1.7	-	nC
Qgs	Gate-Source Charge		-	0.3	-	nC
Qgd	Gate-Drain("Miller") Charge		-	0.6	-	nC
td(on)	Turn-on Delay Time	$V_{DD}=10V, I_D=0.2A, R_{GEN}=10\Omega, V_{GS}=10V,$	-	2	-	ns
tr	Turn-on Rise Time		-	15	-	ns
td(off)	Turn-off Delay Time		-	7	-	ns
t _f	Turn-off Fall Time		-	20	-	ns
IS	Maximum Continuous Drain to Source Diode Forward Current		-	-	0.2	A
ISM	Maximum Pulsed Drain to Source Diode Forward Current		-	-	0.8	A
VSD	Drain to Source Diode Forward Voltage	$V_{GS}=0V, I_S=0.2A$	-	-	1.2	V

Note :

- 1、The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2、The data tested by pulsed , pulse width .The EAS data shows Max. rating .
- 3、The power dissipation is limited by 175 $^{\circ}\text{C}$ junction temperature
- 4、The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation.

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Typical Characteristics

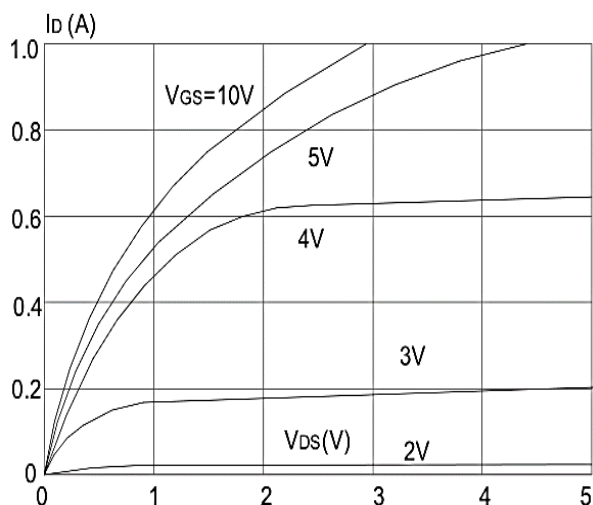


Figure 1: Output Characteristics

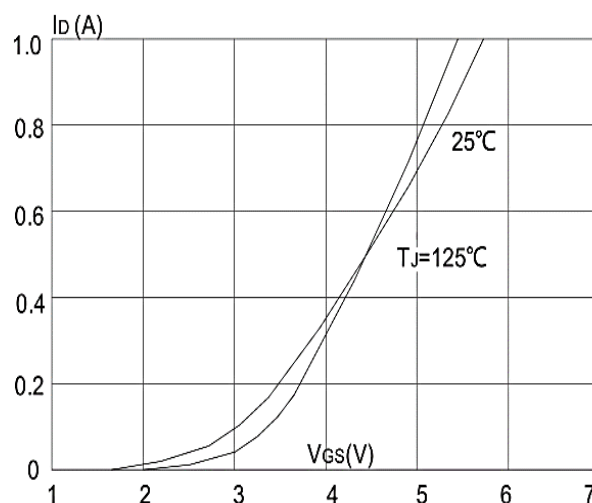


Figure 2: Typical Transfer Characteristics

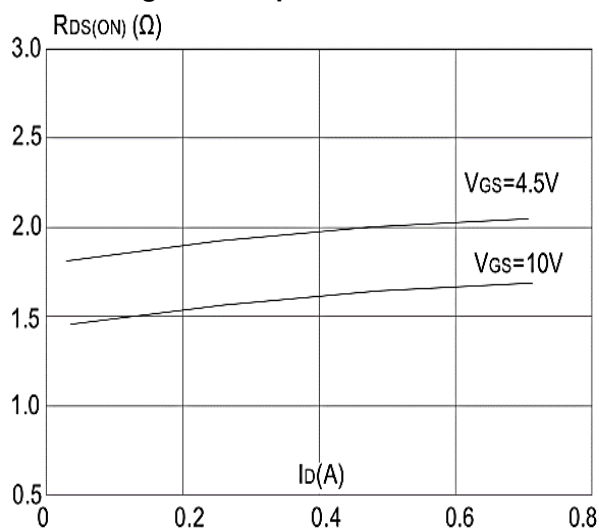


Figure 3: On-resistance vs. Drain Current

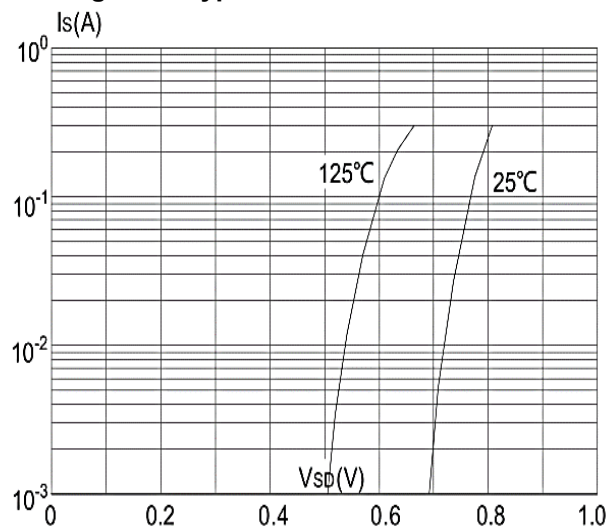


Figure 4: Body Diode Characteristics

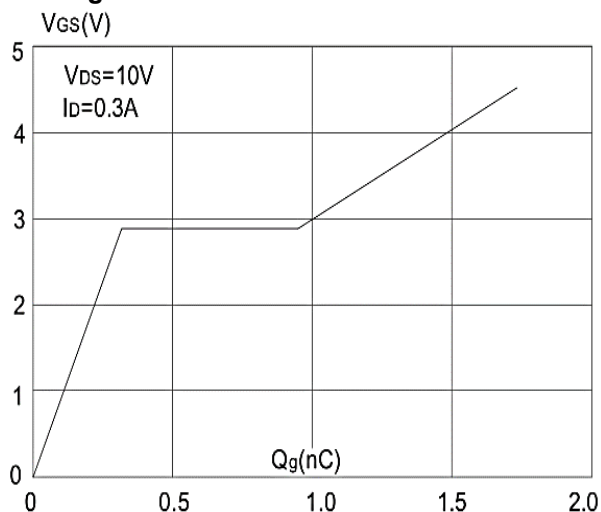


Figure 5: Gate Charge Characteristics

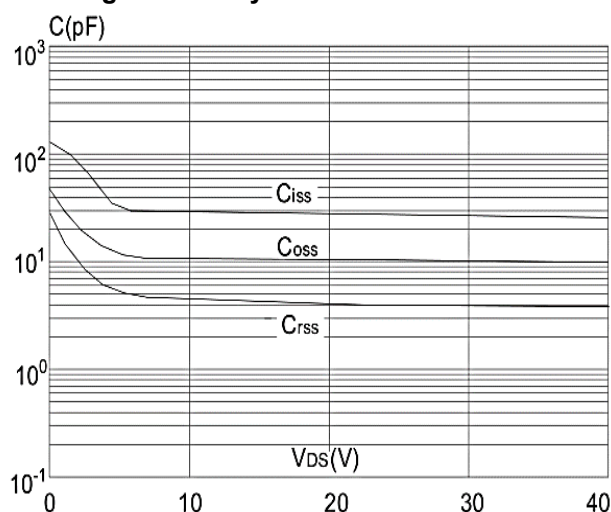


Figure 6: Capacitance Characteristics

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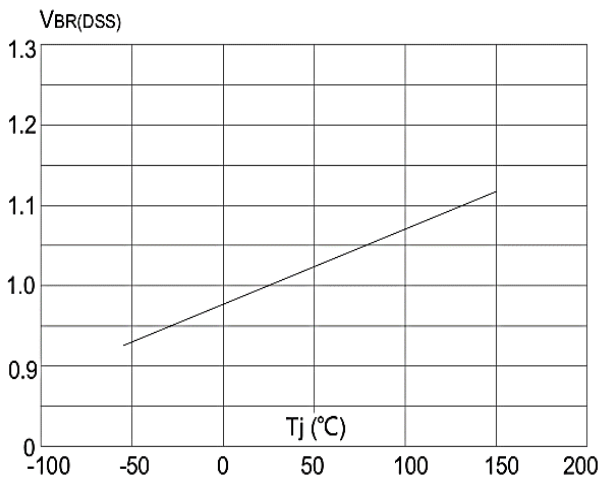


Figure 7: Normalized Breakdown Voltage vs Junction Temperature

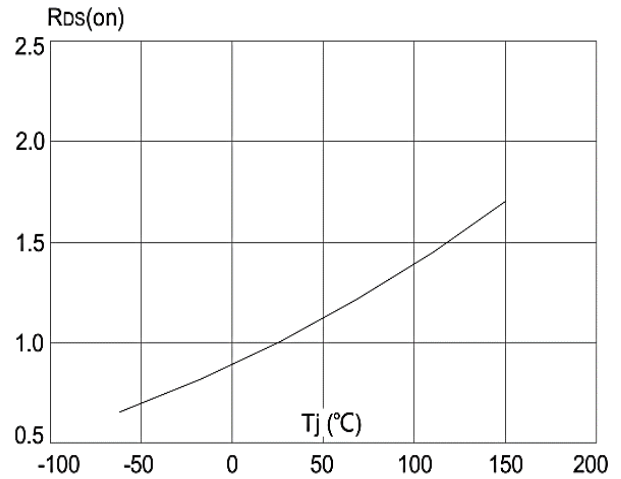


Figure 8: Normalized on Resistance vs. Junction Temperature

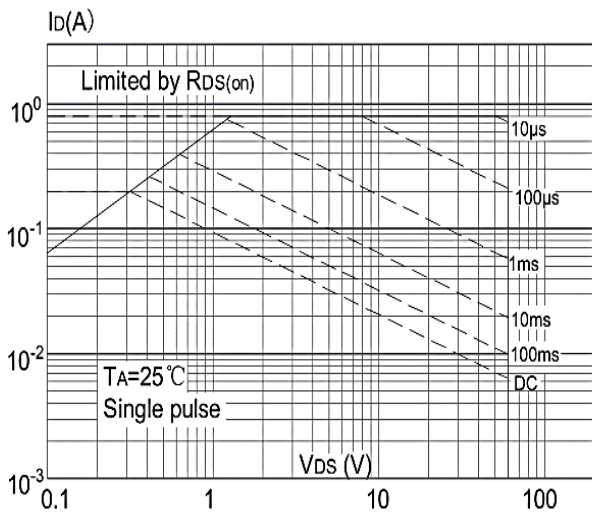


Figure 9: Maximum Safe Operating Area

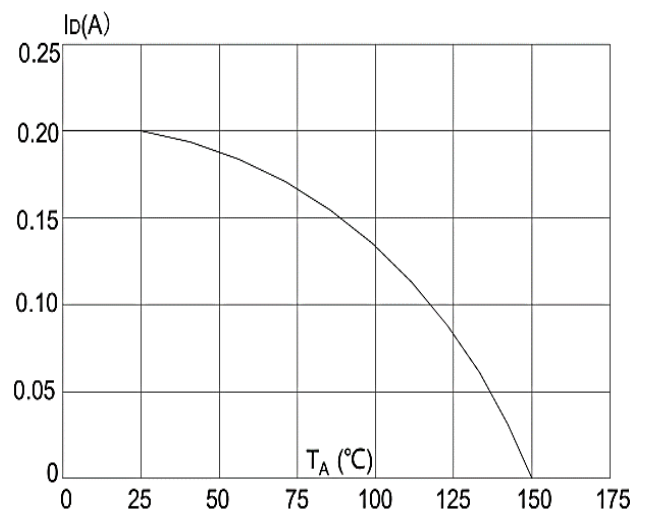


Figure 10: Maximum Continuous Drain Current vs. Ambient Temperature

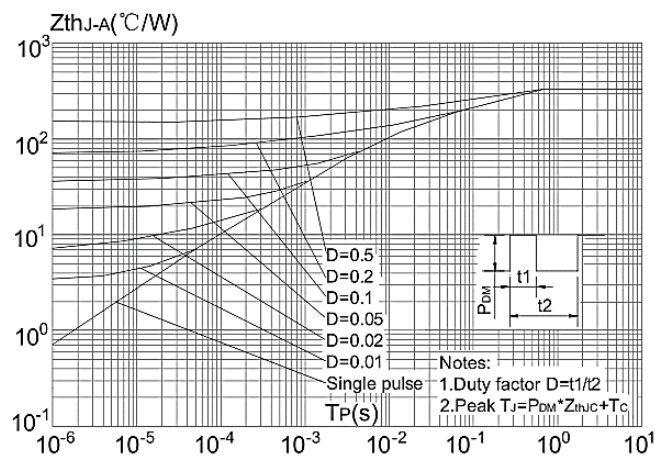
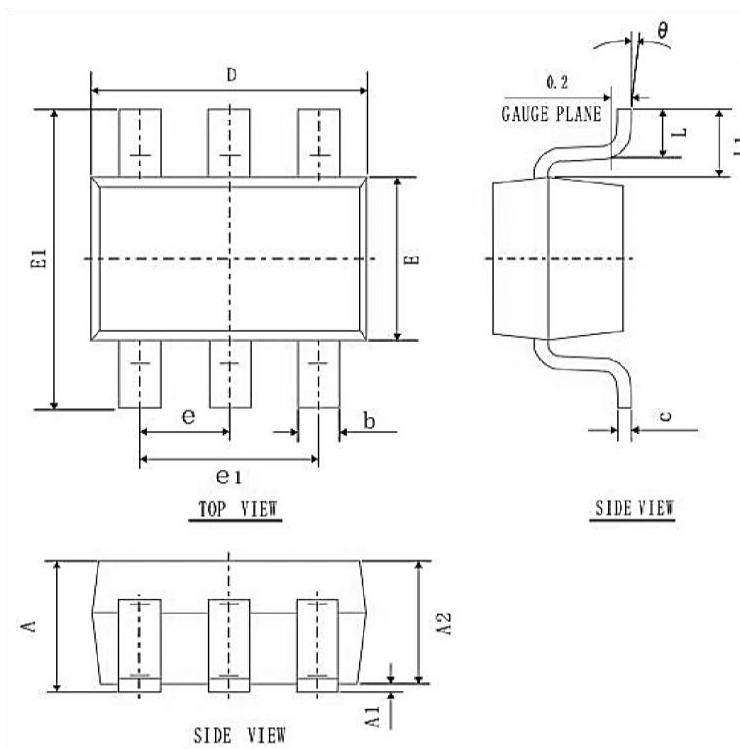


Figure.11: Maximum Effective Transient Thermal Impedance, Junction-to-Ambien

Package Mechanical Data-SOT-363-6L



COMMON DIMENSIONS
(UNITS OF MEASURE=mm)

SYMBOL	MIN	NOM	MAX
A	0.90	1.00	1.10
A1	0.00	0.05	0.10
A2	0.90	0.95	1.00
b	0.20	0.25	0.30
c	0.08	0.10	0.15
e1	1.20	1.30	1.40
D	2.00	2.10	2.20
E	1.15	1.25	1.35
E1	2.15	2.30	2.45
L	0.26	0.36	0.46
θ	0°	4°	8°
L1	0.525 REF		
e	0.65 TYP		

60V N+N-Channel Enhancement Mode MOSFET**Attention**

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Edition	Date	Change
Rve1.0	2020/7/15	Initial release

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